2021 NIST/UL Workshop on Photovoltaic Materials Durability (Agenda)

December 7-9, 2021 9:00 AM-12:15 PM (UTC-05:00) Virtual Meeting

Day 1: Tuesday, December 7, 2021 (9:00 AM-12:15 PM, UTC-5:00)	
8:30 - 9:00 AM	Speakers and Session Chairs Check In (Xiaohong Gu, NIST)
9:00 - 9:15 AM	Opening Remarks Joannie Chin, Acting Director, NIST Engineering Laboratory
	Kenneth Boyce, Director, UL Energy & Power Technologies
Session 1: PV Reliab	ility Programs (Chairs: <u>Kenneth Boyce</u> , UL and Laura Schelhas, NREL)
9:15 - 9:30 AM	DOE SETO Office (Garrett Nilsen, DOE)
9:30 - 9:45 AM	DuraMAT: Material Durability Research Enabling 50-year Modules (Teresa Barnes, NREL)
9:45 - 10:00 AM	IEA-PVPS Task 13: Quality, Durability and Integration of PV in Different Environments & Applications (Ulrike Jahn, VDE Renewable GmbH, Germany)
10:00 - 10:15 AM	Panel Discussion (Chairs: Kenneth Boyce and Laura Schelhas)
Session 2: PV Module	e Circular Economy (Chairs: Aron Newman, NIST and Tadanori Tanahashi, AIST)
10:15 - 10:30 AM	PV CIRCULAR ECONOMY: REGULATORY AND POLICY CONSIDERATIONS (TAYLOR CURTIS, NREL)
10:30 - 10:45 AM	Approaches to Facilitate Responsible PV Module Re-Use (François Rummens, Belgian Electrotechnical Committee, Belgium)
10:45 - 11:00 AM	Increasing the Recyclability of PV Modules (Gernot Oreski, PCCL, Austria)
11:00 - 11:15 AM	Panel Discussion (Chairs: Aron Newman and Tadanori Tanahashi)
Session 3: Climate C Flottemesch, Brookfi	hange and Post-disaster Investigation (Chairs: Nancy Phillips and Robert eld USA)
11:15 - 11:30 AM	Field Failures and Extreme Weather: Findings from Field-testing of Damaged Solar Assets (Jenya Meydbray, PV Evolution Labs)
11:30 - 11:45 AM	Bolted Joint Research - Improving the Resilience of PV Systems (Gerald Robinson, Lawrence Berkeley National Laboratory)
11:45 AM - 12:00 PM	Identifying and Characterizing Fire Related Damage in Solar Modules (Eric Daniels, Suncycle USA)
12:00 PM - 12:15 PM	Panel Discussion (Chairs: Nancy Phillips and Robert Flottemesch)

Day 2: Wednesday, December 8, 2021 (9:00 AM-12:15 PM, UTC-5:00)		
8:30 - 9:00 AM	Speakers and Session Chairs Check In (Xiaohong Gu, NIST)	
Session 4: PV Module Field Performance (Chairs: Colleen O'Brian, UL and John Wohlgemuth, Powerkmark Inc)		
9:00 - 9:15 AM	Testing Methodology, Measurement, and Observation Biases: Insights from 80GW of PV field inspections (Rob Andrews, Heliolytics)	
9:15 - 9:30 AM	Real-World Backsheet Survey (Laura Bruckman, Case Western Reserve University)	
9:30 - 9:45 AM	Electrical Insulation for Field Aged Modules (<u>Tadanori Tanahashi</u> , AIST, Japan)	
9:45 - 10:00 AM	Panel Discussion (Chairs: John Wohlgemuth and Colleen O'Brian)	
Session 5: Accelerated Laboratory Testing (Chairs: Michael Owen-Bellini, NREL and Peter Pasmans, Endurans Solar)		
10:00 - 10:15 AM	Rate of PID-p Progression in n-PERT Cells Depends on Encapsulant Resistivity and Irradiance (Brian Habersberger, Dow)	
10:15 - 10:30 AM	Material Characterization and Durability of Clear Backsheets for Bifacial PV Modules (Xiaohong Gu, NIST)	
10:30 - 10:45 AM	BACKFLIP: A Comparison of Emerging Non-Fluoropolymer-Based, Co-Extruded PV Backsheets to Industry-Benchmark Technologies (David Miller, NREL)	
10:45 - 11:00 AM	Validating IEC TS 63209 Mechanical and Backsheet Degradation Test Legs	
	(Colin Sillerud, CFV LABS)	
11:00 - 11:15 AM	Panel Discussion (Chairs: Peter Pasmans and Michael Owen-Bellini)	
Session 6: Linking Accelerated Laboratory Tests to Field Performance (Chairs: William Gambogi, Xiaohong Gu, NIST)		
11:15 - 11:30 AM	Understanding the Variability Extrapolation from Lab to Field Conditions (Mike Kempe, NREL)	
11:30 - 11:45 AM	Challenges, Opportunities and Approaches for New Service Life Estimation Models for PV Modules- Results of IEA-PVPS-Task 13 (Karl-Anders Weiss, Fraunhofer ISE, Germany)	
11:45 AM - 12:00 PM	Moving from Qualifying Test to Service Life Prediction (James Pickett, Consultant)	
12:00 PM - 12:15 PM	Panel Discussion (Chairs: William Gambogi and Xiaohong Gu)	

Day 3: Thursday, December 9, 2021 (9:00 AM-12:15 PM, UTC-5:00)		
8:30 - 9:00 AM	Speakers and Session Chairs Check In (Xiaohong Gu, NIST)	
Session 7: Character	rization and Modeling (Chairs: David Miller, NERL and Mihail Bora, LLNL)	
9:00- 9:15 AM	Statistical and Deep Learning Methods for Degradation Prediction of Polymeric Materials in PV Systems (Yili Hong, Virginia Tech)	
9:15 - 9:30 AM	Measurement and Simulation of Moisture in PV Modules (Stefan Mitterhofer, NIST)	
9:30 - 9:45 AM	Predicting Performance of PV Modules with Differing UV Absorbers Undergoing UV-Induced Degradation (Peter Hacke, NREL)	
9:45 - 10:00 AM	Panel Discussion (Chairs: David Miller and Mihail Bora)	
Session 8: Linking R	esearch to Standards (Chairs: George Kelly, IEC and Liang Ji, UL)	
10:00 - 10:15 AM	IEC TS 63209-2 AND EXTENDED TESTING OF PV POLYMERIC COMPONENTS (NANCY PHILLIPS)	
10:15 - 10:30 AM	Development of the Front- and Back-sheet Standard (IEC 62788-2-1) (Peter Pasmans, Endurans Solar, The Netherlands)	
10:30 - 10:45 AM	UL Standards Update: Corrosion Testing for PV Applications (Colleen O'Brian, UL)	
10:45 - 11:00 AM	Panel Discussion (Chairs: George Kelly and Liang Ji)	
Session 9: Emerging PV Technology (Chairs: Ingrid Repins, NREL and Stephanie Moffitt, NIST)		
11:00 - 11:15 AM	Perovskite Module Scaling and Stability (Reinhold Dauskardt, Stanford University)	
11:15 - 11:30 AM	Photovoltaics for Vehicles -Similarities and Differences between Standard PV and Car-Component PV (Kenji Araki, University of Miyazaki, Japan)	
11:30 - 11:45 AM	Performance Risks for Building Integrated Photovoltaic Materials, Modules, and Systems (Andrew Fairbrother, EPFL, Switzerland)	
11:45 AM -12:00 PM	Panel Discussion (Chairs: Stephanie Moffitt and Ingrid Repins)	
12:00 PM -12:15 PM	Summary and Adjourn (Kenneth Boyce, UL & Xiaohong Gu, NIST)	

Past NIST PV Workshops can be found:

2019 NIST/UL Workshop on PV Materials Durability

2017 4th NIST/Atlas Workshop on PV Materials Durability

2015 3rd NIST/Atlas Workshop on PV Materials Durability

2013 2nd NIST/Atlas Workshop on PV Materials Durability

2011 1st NIST/Atlas Workshop on PV Materials Durability